

SMD Type Power Inductors

FPI0503F-Series

ECN HISTORY LIST

REV	DATE	DESCRIPTION	APPROVED	CHECKED	DRAWN
1.0	14/07/14	新發行	楊祥忠	詹偉特	徐允珮
備註					

SMD Type Power Inductors

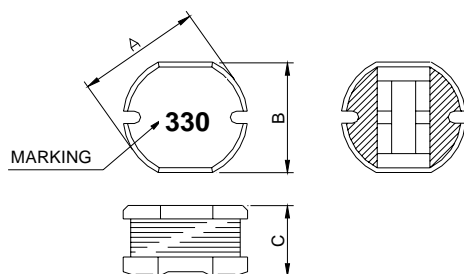
FPI0503F-Series

1. Features

- 1.Excellent solderability and high heat resistance.
- 2.Excellent terminal strength construction.
- 3.Packed in embossed carrier tape and can be used by automatic mounting machine.
- 4.100% Lead(Pb) & Halogen-Free and RoHS compliant.



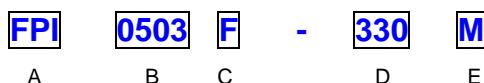
2. Dimension



Size	A(mm)	B(mm)	C(mm)
FPI 0503F	5.80±0.3	5.20±0.3	3.00±0.3

Unit: mm

3. Part Numbering



A: Series

B: Dimension

C: Lead free type

D: Inductance

330=33.0uH

E: Inductance Tolerance

M=±20%

4. Specification

TAI-TECH Part Number	Inductance (uH)		DCR (mΩ) max.	Isat (A) max.	I _{rms} (A) max.
	Tolerance	Test Frequency (Hz)			
FPI0503F-1R0M	1.00±20%	1V/100K	30	4.50	4.50
FPI0503F-1R8M	1.80±20%	1V/7.96M	50	4.00	2.80
FPI0503F-4R7M	4.70±20%	1V/7.96M	70	2.70	2.70
FPI0503F-6R8M	6.80±20%	1V/7.96M	71.2	1.87	1.87
FPI0503F-8R2M	8.20±20%	1V/7.96M	100	2.00	2.00
FPI0503F-100M	10.0±20%	1V/2.52M	200	1.90	1.90
FPI0503F-330M	33.0±20%	1V/2.52M	450	1.40	1.40

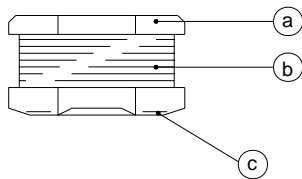
Note

For the parts with inductance under 82 uH , the L is measured at 1MHz then when a Isat current is applied, the L should drop less than 35%.

For the parts with inductance over 100 uH , the L is measured at 1KHz then when a Isat current is applied, the L should drop less than 35%.

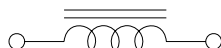
For all FPI series ,when a I_{rms} current is applied, the temperature rised of the parts is less than 40 degree C

5. Material List



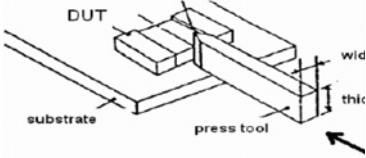
No.	Item	Material
1	Core	Ferrite DR Core
2	Wire	Enamelled Copper wire
3	Terminal	Ag+Ni+Sn

6. Schematic Diagram

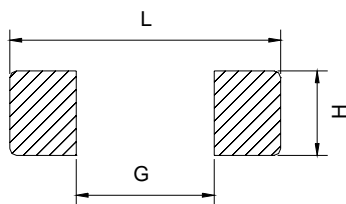


7. Reliability and Test Condition

Item	Performance	Test Condition															
Operating Temperature	-25~+85℃																
Storage temperature	-25~+85℃																
Rated Current	Base on temp. rise & $\Delta L/LOA \leq 35\%$																
Temperature Rise Test	$\Delta t \leq 40^\circ C$																
Life Test		Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles) Temperature : 125±2℃ (Bead) Temperature : 85±2℃ (Inductor) Applied current : rated current Duration : 1000±12hrs Measured at room temperature after placing for 24±2 hrs															
Load Humidity		Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles Humidity : 85±2 % R.H, Temperature : 85℃ ±2℃ Duration : 1000hrs Min. with 100% rated current Measured at room temperature after placing for 24±2 hrs															
Thermal shock		Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles Condition for 1 cycle Step1 : -40±2℃ 30±5min Step2 : 25±2℃ ≤0.5min Step3 : 105±2℃ 30±5min Number of cycles : 500 Measured at room temperature after placing for 24±2 hrs															
Vibration	Appearance : No damage. Inductance : within±10% of initial value Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value	Oscillation Frequency: 10~2K~10Hz for 20 minutes Equipment : Vibration checker Total Amplitude:1.52mm±10% Testing Time : 12 hours(20 minutes, 12 cycles each of 3 orientations) °															
Shock		<table border="1"> <thead> <tr> <th>Type</th> <th>Peak value (g's)</th> <th>Normal duration (D) (ms)</th> <th>Wave form</th> <th>Velocity change (Vj)ft/sec</th> </tr> </thead> <tbody> <tr> <td>SMD</td> <td>1500</td> <td>0.5</td> <td>Half-sine</td> <td>15.4</td> </tr> <tr> <td>Lead</td> <td>100</td> <td>6</td> <td>Half-sine</td> <td>12.3</td> </tr> </tbody> </table>	Type	Peak value (g's)	Normal duration (D) (ms)	Wave form	Velocity change (Vj)ft/sec	SMD	1500	0.5	Half-sine	15.4	Lead	100	6	Half-sine	12.3
Type	Peak value (g's)	Normal duration (D) (ms)	Wave form	Velocity change (Vj)ft/sec													
SMD	1500	0.5	Half-sine	15.4													
Lead	100	6	Half-sine	12.3													
Bending		Shall be mounted on a FR4 substrate of the following dimensions: >=0805:40x100x1.2mm <0805:40x100x0.8mm Bending depth: >=0805:1.2mm <0805:0.8mm duration of 10 sec.															
Soderability	More than 95% of the terminal electrode should be covered with solder °	Preheat: 150℃, 60sec. ° Solder: Sn99.5%-Cu0. 5% ° Temperature: 245±5℃ ° Flux for lead free: Rosin. 9.5% ° Dip time: 4±1sec ° Depth: completely cover the termination															

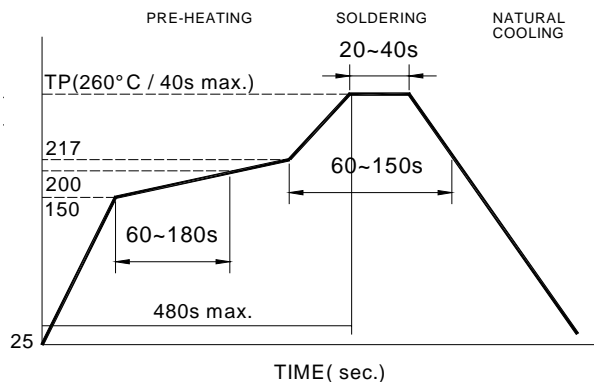
Item	Performance	Test Condition						
Resistance to Soldering Heat		Number of heat cycles: 1 <table border="1" data-bbox="962 275 1347 407"> <thead> <tr> <th>Temperature (°C)</th> <th>Time(s)</th> <th>Temperature ramp/immersion and emersion rate</th> </tr> </thead> <tbody> <tr> <td>260 ±5(solder temp)</td> <td>10 ±1</td> <td>25mm/s ±6 mm/s</td> </tr> </tbody> </table>	Temperature (°C)	Time(s)	Temperature ramp/immersion and emersion rate	260 ±5(solder temp)	10 ±1	25mm/s ±6 mm/s
Temperature (°C)	Time(s)	Temperature ramp/immersion and emersion rate						
260 ±5(solder temp)	10 ±1	25mm/s ±6 mm/s						
Terminal Strength	Appearance : No damage. Inductance : within±10% of initial value Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value	Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles With the component mounted on a PCB with the device to be tested, apply a force (>0805:1kg , <=0805:0.5kg)to the side of a device being tested. This force shall be applied for 60 +1 seconds. Also the force shall be applied gradually as not to apply a shock to the component being tested. 						

8. Recommended PC Board Pattern



L(mm)	G(mm)	H(mm)
6.0	1.7	5.5

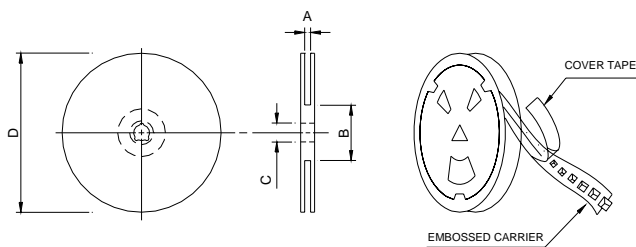
Reflow Soldering



Reflow times: 3 times max.

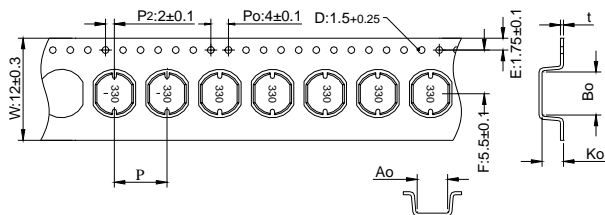
9. Packaging Information

9-1. Reel Dimension



Type	A(mm)	B(mm)	C(mm)	D(mm)
13"x12mm	14 ⁺⁰	100 ⁰	13±0.5	330

9-2.1 Tape Dimension / 12mm

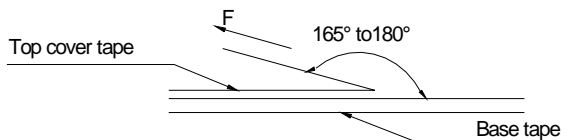


Size	Bo(mm)	Ao(mm)	Ko(mm)	P(mm)	t(mm)
0503	6.0±0.1	5.7±0.1	3.3±0.1	8.0±0.1	0.35±0.05

9-3. Packaging Quantity

Size	0503
Chip / Reel	2000
Inner box	8000
Carton	32000

9-4. Tearing Off Force



The force for tearing off cover tape is 5 to 120 grams in the arrow direction under the following conditions.

Room Temp. (°C)	Room Humidity (%)	Room atm (hPa)	Tearing Speed mm/min
5-35	45-85	860-1060	300

Application Notice

- Storage Conditions (component level)

To maintain the solderability of terminal electrodes:

 1. TAI-TECH products meet IPC/JEDEC J-STD-020D standard-MSL, level 1.
 2. Temperature and humidity conditions: Less than 40°C and 60% RH.
 3. Recommended products should be used within 12 months form the time of delivery.
 4. The packaging material should be kept where no chlorine or sulfur exists in the air.
- Transportation
 1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
 2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
 3. Bulk handling should ensure that abrasion and mechanical shock are minimized.

測試報告

Test Report

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西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

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(桃園縣中壢市中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JHONGLI CITY, TAOYUAN COUNTY 320, TAIWAN)

以下測試樣品係由申請廠商所提供及確認 (The following sample(s) was/were submitted and identified by/on behalf of the applicant as) :

樣品名稱(Sample Description) : WINDING POWER INDUCTOR/SMD POWER INDUCTOR
樣品型號(Style/Item No.) : LQN, LQC, FPI, FPIG, FPIP SERIES
收件日期(Sample Receiving Date) : 2014/06/04
測試期間(Testing Period) : 2014/06/04 TO 2014/06/11

測試結果(Test Results) : 請見下一頁 (Please refer to next pages).


Troy Chang, Manager - Tech
Signed for and on behalf of
SGS TAIWAN LTD.
Chemical Laboratory - Taipei

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測試結果(Test Results)

測試部位(PART NAME)No.1 : 整體混測 (MIXED ALL PARTS)

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				No.1
鎘 / Cadmium (Cd)	mg/kg	參考IEC 62321-5: 2013方法, 以感應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-5: 2013 and performed by ICP-AES.	2	n.d.
鉛 / Lead (Pb)	mg/kg	參考IEC 62321-5: 2013方法, 以感應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-5: 2013 and performed by ICP-AES.	2	n.d.
汞 / Mercury (Hg)	mg/kg	參考IEC 62321-4: 2013方法, 以感應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-4: 2013 and performed by ICP-AES.	2	n.d.
六價鉻 / Hexavalent Chromium Cr(VI)	mg/kg	參考IEC 62321: 2008方法, 以UV-VIS檢測. / With reference to IEC 62321: 2008 and performed by UV-VIS.	2	n.d.
六溴環十二烷及所有主要被辨別出的異構物 / Hexabromocyclododecane (HBCDD) and all major diastereoisomers identified (α - HBCDD, β - HBCDD, γ - HBCDD) (CAS No.: 25637-99-4 and 3194-55-6 (134237-51-7, 134237-50-6, 134237-52-8))	mg/kg	參考IEC 62321: 2008方法, 以氣相層析/質譜儀檢測. / With reference to IEC 62321: 2008 method. Analysis was performed by GC/MS.	5	n.d.

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				No.1
鄰苯二甲酸甲苄基丁酯 / BBP (Benzyl butyl phthalate) (CAS No.: 85-68-7)	%	參考EN 14372, 以氣相層析/質譜儀檢測。 / With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
鄰苯二甲酸二(2-乙基己基)酯 / DEHP (Di-(2-ethylhexyl) phthalate) (CAS No.: 117-81-7)	%	參考EN 14372, 以氣相層析/質譜儀檢測。 / With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
鄰苯二甲酸二異癸酯 / DIDP (Di-isodecyl phthalate) (CAS No.: 26761-40-0; 68515-49-1)	%	參考EN 14372, 以氣相層析/質譜儀檢測。 / With reference to EN 14372. Analysis was performed by GC/MS.	0.01	n.d.
鄰苯二甲酸二異壬酯 / DINP (Di-isononyl phthalate) (CAS No.: 28553-12-0; 68515-48-0)	%	參考EN 14372, 以氣相層析/質譜儀檢測。 / With reference to EN 14372. Analysis was performed by GC/MS.	0.01	n.d.
鄰苯二甲酸二正辛酯 / DNOP (Di-n-octyl phthalate) (CAS No.: 117-84-0)	%	參考EN 14372, 以氣相層析/質譜儀檢測。 / With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
鄰苯二甲酸二丁酯 / DBP (Dibutyl phthalate) (CAS No.: 84-74-2)	%	參考EN 14372, 以氣相層析/質譜儀檢測。 / With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
鄰苯二甲酸二異丁酯 / DIBP (Di-isobutyl phthalate) (CAS No.: 84-69-5)	%	參考EN 14372, 以氣相層析/質譜儀檢測。 / With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值	結果 (Result)
			(MDL)	No. 1
多溴聯苯總和 / Sum of PBBs	mg/kg	參考IEC 62321: 2008方法, 以氣相層析/質譜儀檢測. / With reference to IEC 62321: 2008 and performed by GC/MS.	-	n.d.
一溴聯苯 / Monobromobiphenyl	mg/kg		5	n.d.
二溴聯苯 / Dibromobiphenyl	mg/kg		5	n.d.
三溴聯苯 / Tribromobiphenyl	mg/kg		5	n.d.
四溴聯苯 / Tetrabromobiphenyl	mg/kg		5	n.d.
五溴聯苯 / Pentabromobiphenyl	mg/kg		5	n.d.
六溴聯苯 / Hexabromobiphenyl	mg/kg		5	n.d.
七溴聯苯 / Heptabromobiphenyl	mg/kg		5	n.d.
八溴聯苯 / Octabromobiphenyl	mg/kg		5	n.d.
九溴聯苯 / Nonabromobiphenyl	mg/kg		5	n.d.
十溴聯苯 / Decabromobiphenyl	mg/kg		5	n.d.
多溴聯苯醚總和 / Sum of PBDEs	mg/kg		-	n.d.
一溴聯苯醚 / Monobromodiphenyl ether	mg/kg		5	n.d.
二溴聯苯醚 / Dibromodiphenyl ether	mg/kg		5	n.d.
三溴聯苯醚 / Tribromodiphenyl ether	mg/kg		5	n.d.
四溴聯苯醚 / Tetrabromodiphenyl ether	mg/kg		5	n.d.
五溴聯苯醚 / Pentabromodiphenyl ether	mg/kg		5	n.d.
六溴聯苯醚 / Hexabromodiphenyl ether	mg/kg		5	n.d.
七溴聯苯醚 / Heptabromodiphenyl ether	mg/kg		5	n.d.
八溴聯苯醚 / Octabromodiphenyl ether	mg/kg		5	n.d.
九溴聯苯醚 / Nonabromodiphenyl ether	mg/kg	5	n.d.	
十溴聯苯醚 / Decabromodiphenyl ether	mg/kg	5	n.d.	

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測試報告

Test Report

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值	結果 (Result)
			(MDL)	No.1
鹵素 / Halogen				
鹵素 (氟) / Halogen-Fluorine (F) (CAS No.: 14762-94-8)	mg/kg	參考BS EN 14582:2007, 以離子層析儀分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.
鹵素 (氯) / Halogen-Chlorine (Cl) (CAS No.: 22537-15-1)	mg/kg		50	n.d.
鹵素 (溴) / Halogen-Bromine (Br) (CAS No.: 10097-32-2)	mg/kg		50	n.d.
鹵素 (碘) / Halogen-Iodine (I) (CAS No.: 14362-44-8)	mg/kg		50	n.d.

備註(Note):

1. mg/kg = ppm; 0.1wt% = 1000ppm
2. n.d. = Not Detected (未檢出)
3. MDL = Method Detection Limit (方法偵測極限值)
4. "-" = Not Regulated (無規格值)
5. 樣品的測試是基於申請人要求混合測試, 報告中的混合測試結果不代表其中個別單一材質的含量. (The samples was/were analyzed on behalf of the applicant as mixing sample in one testing. The above results was/were only given as the informality value.)

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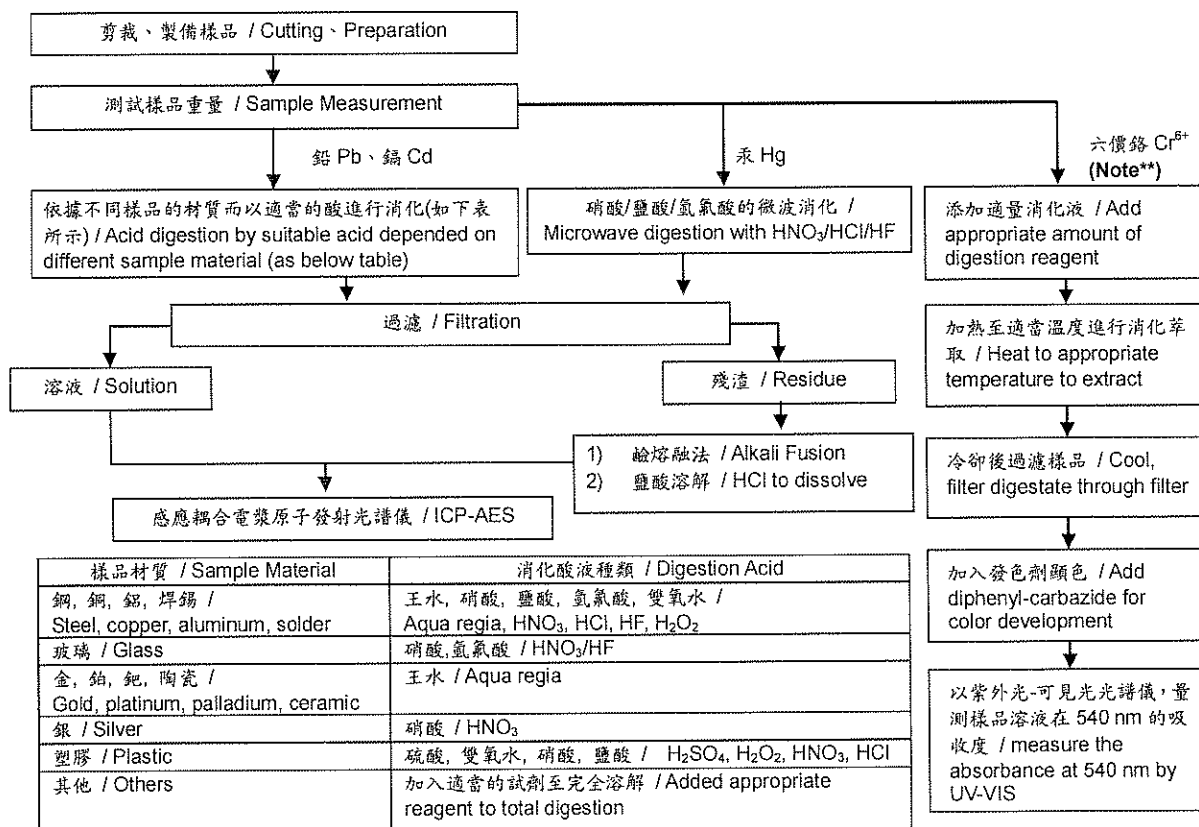
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- 1) 根據以下的流程圖之條件，樣品已完全溶解。(六價鉻測試方法除外) / These samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr⁶⁺ test method excluded)
- 2) 測試人員：楊登偉 / Name of the person who made measurement: Climgreat Yang
- 3) 測試負責人：張啓興 / Name of the person in charge of measurement: Troy Chang



Note** (For IEC 62321)

- (1) 針對非金屬材料加入鹼性消化液，加熱至 90~95°C 萃取。 / For non-metallic material, add alkaline digestion reagent and heat to 90~95°C.
- (2) 針對金屬材料加入純水，加熱至沸騰萃取。 / For metallic material, add pure water and heat to boiling.

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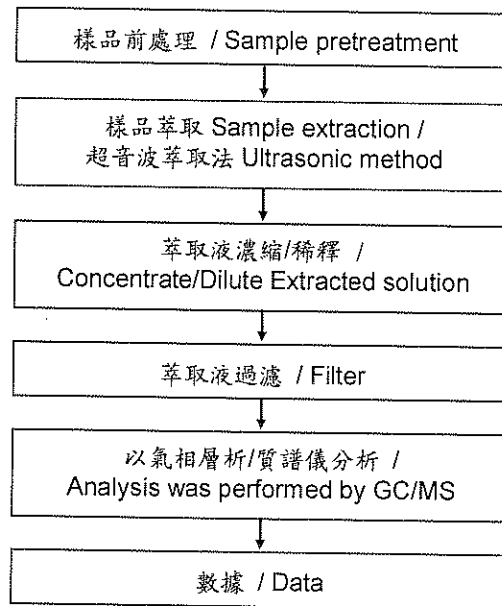
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六溴環十二烷分析流程圖 / HBCDD analytical flow chart

- 測試人員：翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人：張啓興 / Name of the person in charge of measurement: Troy Chang



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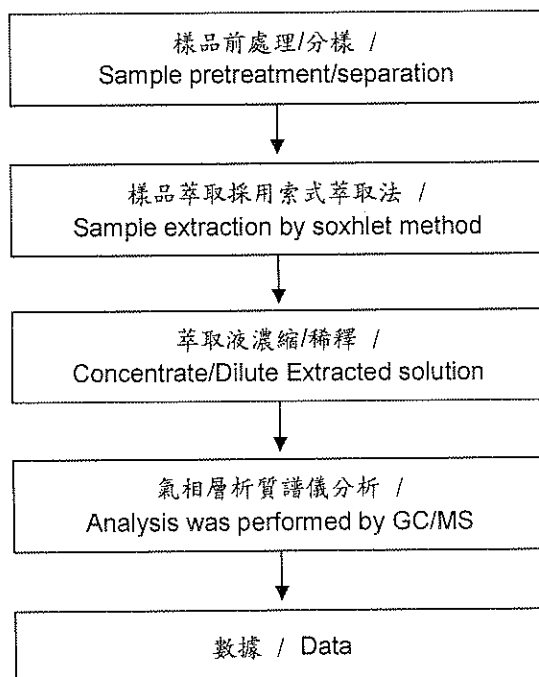
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可塑劑分析流程圖 / Analytical flow chart of phthalate content

- 測試人員：翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人：張啓興 / Name of the person in charge of measurement: Troy Chang



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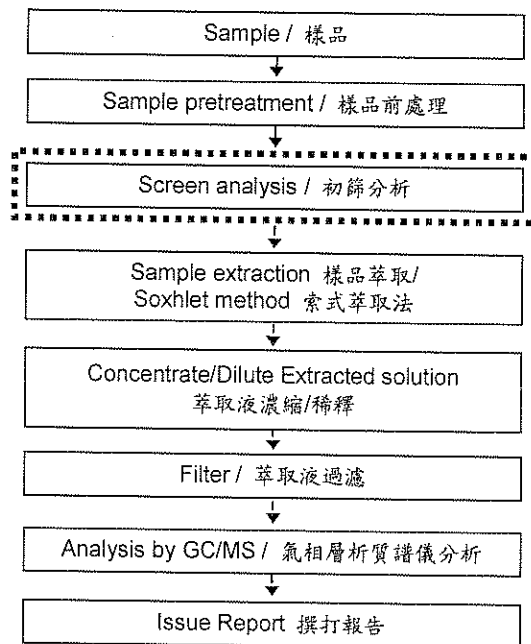
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多溴聯苯/多溴聯苯醚分析流程圖 / PBB/PBDE analytical FLOW CHART

- 測試人員：翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人：張啓興 / Name of the person in charge of measurement: Troy Chang
- 初次測試程序 / First testing process —————>
- 選擇性篩檢程序 / Optional screen process>
- 確認程序 / Confirmation process - - ->



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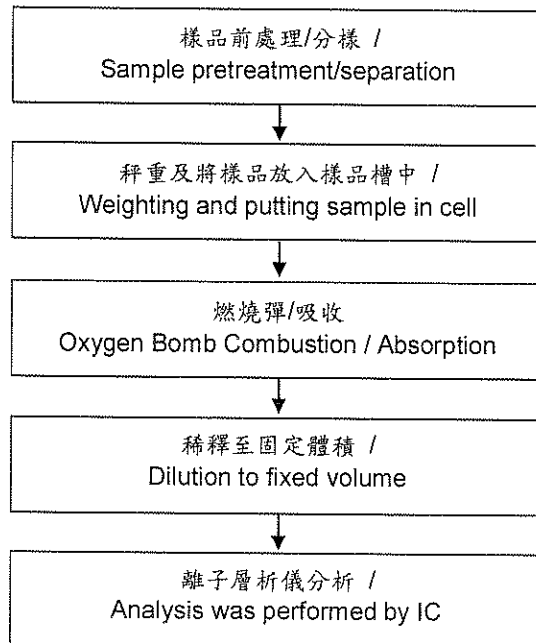
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鹵素分析流程圖 / Analytical flow chart of halogen content

- 測試人員：陳恩臻 / Name of the person who made measurement: Rita Chen
- 測試負責人：張啓興 / Name of the person in charge of measurement: Troy Chang



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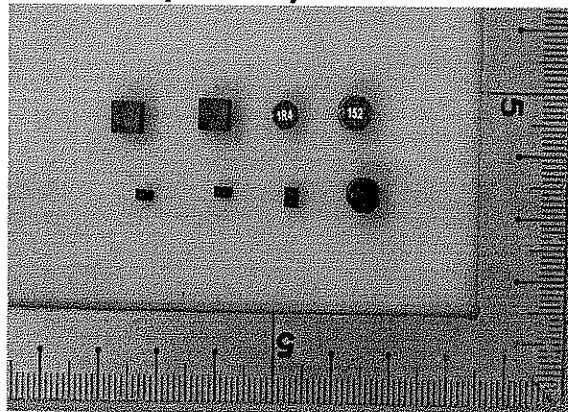
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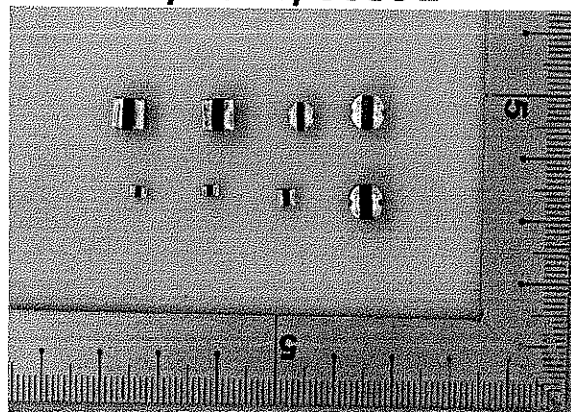
* 照片中如有箭頭標示，則表示為實際檢測之樣品/部位。 *

(The tested sample / part is marked by an arrow if it's shown on the photo.)

CE/2014/60591



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